

VNH50N04

"OMNIFET": FULLY AUTOPROTECTED POWER MOSFET

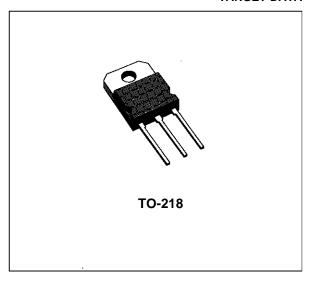
TARGET DATA

TYPE	V _{clamp}	R _{DS(on)}	l _{lim}
VNH50N04	40 V	0.012 Ω	50 A

- LINEAR CURRENT LIMITATION
- THERMAL SHUT DOWN
- SHORT CIRCUIT PROTECTION
- INTEGRATED CLAMP
- LOW CURRENT DRAWN FROM INPUT PIN
- DIAGNOSTIC FEEDBACK THROUGH INPUT PIN
- ESD PROTECTION
- DIRECT ACCESS TO THE GATE OF THE POWER MOSFET (ANALOG DRIVING)
- COMPATIBLE WITH STANDARD POWER MOSFET
- STANDARD TO-218 PACKAGE

DESCRIPTION

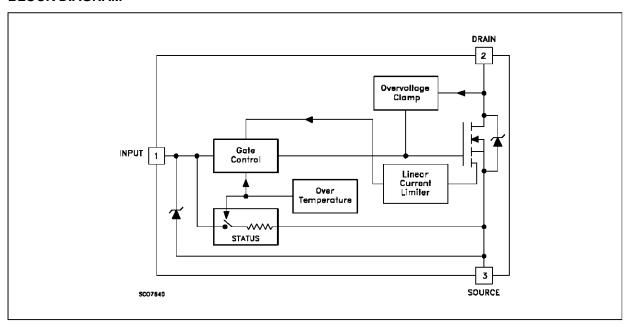
The VNH50N04 is a monolithic device made using SGS-THOMSON Vertical Intelligent Power M0 Technology, intended for replacement of standard power MOSFETS in DC to 50 KHz applications. Buit-in thermal shut-down, linear



current limitation and overvoltage clamp protect the chip in harsh environments.

Fault feedback can be detected by monitoring the voltage at the input pin.

BLOCK DIAGRAM



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ABSOLUTE MAXIMUM RATING

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source Voltage (V _{in} = 0)	Internally Clamped	V
Vin	Input Voltage	18	V
I _D	Drain Current	Internally Limited	Α
I _R	Reverse DC Output Current	-50	Α
V _{esd}	Electrostatic Discharge (C= 100 pF, R=1.5 KΩ)	2000	V
P _{tot}	Total Dissipation at T _c = 25 °C	208	W
_{J.com} T _j	Operating Junction Temperature	Internally Limited	°C
Tc	Case Operating Temperature	Internally Limited	°C
T _{stg}	Storage Temperature	-55 to 150	°C

THERMAL DATA

ELECTRICAL CHARACTERISTICS ($T_{case} = 25$ $^{\circ}C$ unless otherwise specified) OFF

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V_{CLAMP}	Drain-source Clamp Voltage	I _D = 18 A V _{in} = 0	31		45	V
V _{CLTH}	Drain-source Clamp Threshold Voltage	$I_D = 2 \text{ mA}$ $V_{in} = 0$	30			V
VINCL	Input-Source Reverse Clamp Voltage	I _{in} = -1 mA	-1		-0.3	V
I _{DSS}	Zero Input Voltage Drain Current (V _{in} = 0)	V _{DS} = 13 V V _{DS} = 25 V			50 200	μA μA
I _{ISS}	Supply Current from Input Pin	V _{DS} = 0 V V _{in} = 8 V		250	500	μΑ

ON (*)

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{IS(th)}	Input Threshold Voltage	$V_{DS} = V_{in}$ $I_D = 1$ mA	1		3	V
R _{DS(on)}	Static Drain-source On Resistance	$V_{in} = 10 \text{ V}$ $I_D = 30 \text{ A}$ $V_{in} = 5 \text{ V}$ $I_D = 30 \text{ A}$			0.012 TBD	Ω

DYNAMIC

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
g _{fs} (*)	Forward Transconductance	V _{DS} = 13 V I _D = 30 A		40		S
Coss	Output Capacitance	$V_{DS} = 13 V$ f = 1 MHz $V_{in} = 0$		1800	3000	pF

ELECTRICAL CHARACTERISTICS (continued)

SWITCHING

	Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
	$t_{ m d(on)} \ t_{ m r} \ t_{ m d(off)} \ t_{ m f}$	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\begin{array}{ll} V_{DD} = 15 \ V & I_d = 30 \ A \\ V_{gen} = 10 \ V & R_{gen} = 10 \ \Omega \\ (see \ figure \ 3) & \end{array}$		100 200 700 350	TBD TBD TBD TBD	ns ns ns ns
4U	$t_{d(on)} \ t_r \ t_{d(off)} \ .$ com t_f	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$V_{DD} = 15 \text{ V}$ $I_{d} = 30 \text{ A}$ $V_{gen} = 10 \text{ V}$ $R_{gen} = 10 \Omega$ $T_{j} = 125 ^{\circ}\text{C}$ (see figure 3)		100 350 1000 650	TBD TBD TBD TBD	ns ns ns ns
	$t_{d(on)} \ t_r \ t_{d(off)} \ t_f$	Turn-on Delay Time Rise Time Turn-off Delay Time Fall Time	$\begin{array}{ll} V_{DD} = 15 \ V & I_d = 30 \ A \\ V_{gen} = 10 \ V & R_{gen} = 1000 \ \Omega \\ (\text{see figure 3}) & \end{array}$		1.9 5.7 20 12	TBD TBD TBD TBD	μs μs μs μs
	(di/dt) _{on}	Turn-on Current Slope	V _{DD} = 15 V I _D = 30 A V _{in} = 10 V		TBD		A/μs
	Qg	Total Gate Charge	$V_{DD} = 12 \text{ V}$ $I_D = 30 \text{ A}$ $V_{in} = 10 \text{ V}$		TBD		nC

SOURCE DRAIN DIODE

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
V _{SD} (*)	Forward On Voltage	I _{SD} = 30 A V _{in} = 0		0.86	TBD	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 30 \text{ A}$ $di/dt = 100 \text{ A/}\mu\text{s}$ $V_{DD} = V$ $T_i = 150 ^{\circ}\text{C}$		TBD		ns
Q _{rr}	Reverse Recovery Charge	(see test circuit, figure 5)		TBD		μС
I _{RRM}	Reverse Recovery Current			TBD		А

PROTECTION

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
I _{lim}	Drain Current Limit	V _{in} = 10 V V _{DS} = 13 V	35	50	65	Α
t _{dlim}	Step Response Current Limit	V _{in} = 10 V V _{DS} = 13V		40	80	μs
T _{jsh}	Overtemperature Shutdown		150	170	190	°C
T _{jrs}	Overtemperature Reset		135			°C
I _{gf}	Fault Sink Current	V _{in} = 10 V V _{DS} = 13 V		50		mA
Eas	Single Pulse Avalanche Energy	starting $T_j = 25$ °C $V_{DD} = 20$ V $V_{in} = 10$ V $R_{gen} = 1$ K Ω L = 1.6 mH	5			J

^(*) Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

PROTECTION FEATURES

During normal operation, the Input pin is electrically connected to the gate of the internal power MOSFET. The device then behaves like a standard power MOSFET and can be used as a switch from DC to 50 KHz. The only difference from the user's standpoint is that a small DC current (I_{iss}) flows into the Input pin in order to supply the internal circuitry.

The device integrates:

- OVERVOLTAGE CLAMP PROTECTION: internally set at 42V, along with the rugged avalanche characteristics of the Power MOSFET stage give this device unrivalled ruggedness and energy handling capability. This feature is mainly important when driving inductive loads.
- LINEAR CURRENT LIMITER CIRCUIT: limits the drain current ld to llim whatever the Input pin voltage. When the current limiter is active, the device operates in the linear region, so power dissipation may exceed the capability of the heatsink. Both case and junction temperatures increase, and if this phase lasts long enough, junction temperature may reach the overtemperature threshold T_{jsh}.

- OVERTEMPERATURE AND SHORT CIRCUIT PROTECTION: these are based on sensing the chip temperature and are not dependent on the input voltage. The location of the sensing element on the chip in the power stage area ensures fast, accurate detection of the junction temperature. Overtemperature cutout occurs in the range 150 to 190°C, a typical value being 170°C. The device is automatically restarted when the chip temperature falls below 135°C.
- STATUS FEEDBACK: In the case of an overtemperature fault condition, a Status Feedback is provided through the Input pin. The internal protection circuit disconnects the input from the gate and connects it instead to ground via an equivalent resistance of 200 Ω . The failure can be detected by monitoring the voltage at the Input pin, which will be close to ground potential.

Additional features of this device are ESD protection according to the Human Body model and the ability to be driven from a TTL Logic circuit (with a small increase in R_{DS(on)}).

Fig. 1: Unclamped Inductive Load Test Circuits

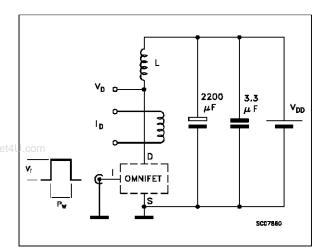


Fig. 3: Switching Times Test Circuits For Resistive Load

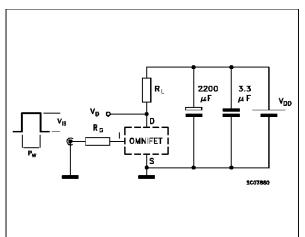


Fig. 5: Test Circuit For Inductive Load Switching And Diode Recovery Times

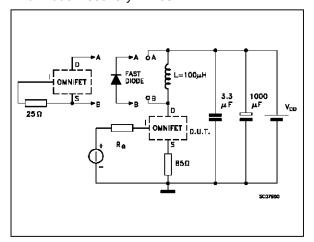


Fig. 2: Unclamped Inductive Waveforms

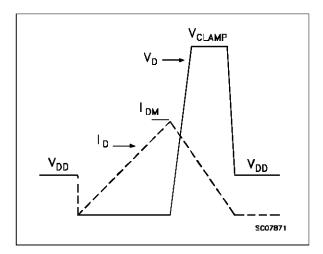


Fig. 4: Input Charge Test Circuit

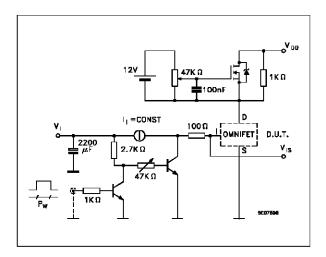
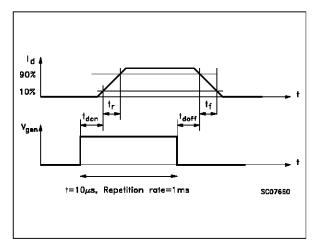
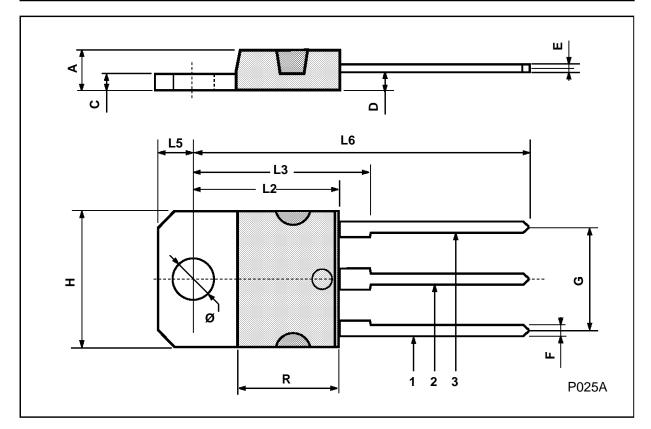


Fig. 6: Waveforms



TO-218 (SOT-93) MECHANICAL DATA

	DIM.		mm			inch	
	Dilwi.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
	А	4.7		4.9	0.185		0.193
	С	1.17		1.37	0.046		0.054
ww.DataSheet4L	l.com D		2.5			0.098	
	E	0.5		0.78	0.019		0.030
	F	1.1		1.3	0.043		0.051
	G	10.8		11.1	0.425		0.437
	Н	14.7		15.2	0.578		0.598
	L2	_		16.2	_		0.637
	L3		18			0.708	
	L5	3.95		4.15	0.155		0.163
	L6		31			1.220	
	R	_		12.2	_		0.480
	Ø	4		4.1	0.157		0.161



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